

Preliminary Amendment

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Serial No.: Unknown

(Priority Application No. DE 103 38 922.9)

(International Application No. PCT/DE2004/001799)

Filed: Herewith

(Priority Date: August 20, 2003)

(International Filing Date: August 11, 2004)

Docket No.: I431.151.101/FIN 504 PCT

Title: ELECTRICAL DIAGNOSTIC CIRCUIT AND METHOD FOR THE TESTING AND/OR THE
DIAGNOSTIC ANALYSIS OF AN INTEGRATED CIRCUIT

IN THE ABSTRACT

Please replace the Abstract with the following rewritten paragraph:

| Abstract

**ELECTRICAL DIAGNOSTIC CIRCUIT AND METHOD FOR THE TESTING
AND/OR THE DIAGNOSTIC ANALYSIS OF AN INTEGRATED CIRCUIT**

Abstract

An electrical diagnostic circuit and testing method is disclosed. In one embodiment,
The electrical diagnostic circuit for testing an integrated circuit ~~comprises~~includes a number
of external inputs-(E), a plurality of essentially similar, series-connected switching units and a
circuit output-(116). The switching units are constructed to be controllable in such a manner
that an input signal present at the internal input of the switching unit, in dependence on a
control signal of the switching unit, can either be forwarded unchanged to the internal input
of the switching unit in each case arranged downstream, or can be combined with the test
signal in each case present at the external input-(E).

| (Figure 1)